Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10618829	MEYER ET AL.	
Examiner	Art Unit	
Kiss, Eric B.	2192	

SEARCHED					
Class	Subclass	Date	Examiner		
717	114, 117, 135, 140, 174	12/07/2007	EBK		
719	328	12/07/2007	EBK		
714	28, 30, 31	12/07/2007	EBK		

SEARCH NOTES				
Search Notes	Date	Examiner		
Plus Search	10/30/2006	JJR		
East (see attached search notes)	10/30/2006	JJR		
Palm Inventor Search	10/30/2006	JJR		
Google (test bench co-simulation)	1/02/2006	JJR		
IEEE (see attached search notes)	1/5/2006	JJR		
ACM/PORTAL (see attached search notes)	1/05/2006	JJR		
updated EAST search (see search history printout)	12/07/2007	EBK		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
	Interference searched (US-PGPUB; text searchsee search history printout)	12/07/2007	EBK	